PATENT

March 27, 2007

HE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.:

10/791,629

Filing Date:

March 3, 2004

Applicant:

Soo-Chan LEE et al.

Group Art Unit:

2829

Examiner:

Jermele M. Hollington

Title:

SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR

DEVICES

Attorney Docket:

2421-000033/US

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Alexandria, VA 22314

Mail Stop Amendment AF

AMENDMENT UNDER 37 C.F.R. § 1.116

Sir:

In response to the Final Office Action mailed December 27, 2006, the following remarks are respectfully submitted in connection with the above-identified application.

Listing of the Claims begin on page 2 of this Amendment.

Remarks begin on page 16 of this Amendment.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	40	-	42	=	0
Independent	13	-	13	=	0

Dorot